

Document Title

512K x16 bit Super Low Power and Low Voltage Full CMOS Static RAM

Revision History

Revision No.	History	Draft Date	Remark
0.0	Initial draft	July 23, 1999	Preliminary

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512K x 16 bit Super Low Power and Low Voltage Full CMOS Static RAM

FEATURES

- Process Technology: Full CMOS
- Organization: 512K x16
- Power Supply Voltage: 3.0~3.6V
- Low Data Retention Voltage: 1.5V(Min)
- Three state output and TTL Compatible
- Package Type: 44-TSOP2-400F/R

GENERAL DESCRIPTION

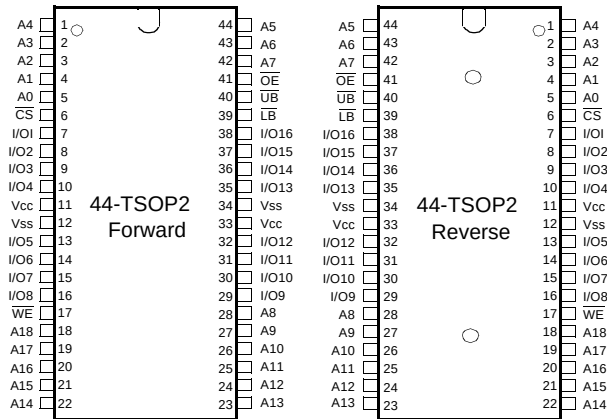
The KM616FV8000 families are fabricated by SAMSUNG's advanced full CMOS process technology. The families support various operating temperature ranges and have small package for user flexibility of system design. The families also support low data retention voltage for battery back-up operation with low data retention current.

PRODUCT FAMILY

Product Family	Operating Temperature	Vcc Range	Speed	Power Dissipation		PKG Type
				Standby (I _{SB1} , Typ.)	Operating (I _{CC1} , Max)	
KM616FV8000	Commercial(0~70°C)	3.0~3.6V	55 ¹⁾ /70ns	0.5μA	4mA	44-TSOP2-400F/R
KM616FV8000I	Industrial(-40~85°C)					

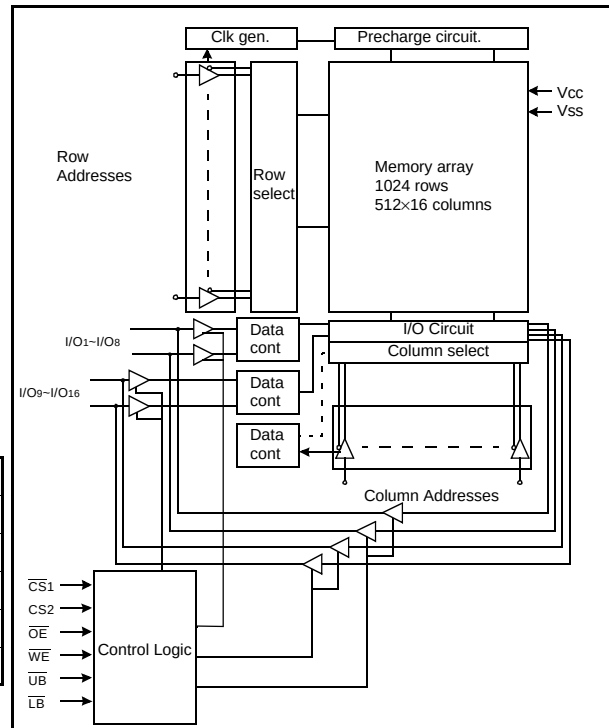
1. The parameter is measured with 30pF test load.

PIN DESCRIPTION



Name	Function	Name	Function
$\overline{CS}$	Chip Select Input	Vcc	Power
$\overline{OE}$	Output Enable Input	Vss	Ground
$\overline{WE}$	Write Enable Input	$\overline{UB}$	Upper Byte(I/O ₉ ~16)
A ₀ ~A ₁₈	Address Inputs	$\overline{LB}$	Lower Byte(I/O ₁ ~8)
I/O ₁ ~I/O ₁₆	Data Inputs/Outputs		

FUNCTIONAL BLOCK DIAGRAM



SAMSUNG ELECTRONICS CO., LTD. reserves the right to change products and specifications without notice.

PRODUCT LIST

Commercial Temperature Products(0~70°C)		Industrial Temperature Products(-40~85°C)	
Part Name	Function	Part Name	Function
KM616FV8000T-5 KM616FV8000T-7	44-TSOP2-F, 55ns, 3.3V 44-TSOP2-F, 70ns, 3.3V	KM616FV8000TI-5 KM616FV8000TI-7	44-TSOP2-F, 55ns, 3.3V 44-TSOP2-F, 70ns, 3.3V
KM616FV8000R-5 KM616FV8000R-7	44-TSOP2-R, 55ns, 3.3V 44-TSOP2-R, 70ns, 3.3V	KM616FV8000TI-5 KM616FV8000TI-7	44-TSOP2-R, 55ns, 3.3V 44-TSOP2-R, 70ns, 3.3V

FUNCTIONAL DESCRIPTION

$\overline{\text{CS}}$	$\overline{\text{OE}}$	$\overline{\text{WE}}$	$\overline{\text{LB}}$	$\overline{\text{UB}}$	I/O1~8	I/O9~16	Mode	Power
H	X	X	X	X	High-Z	High-Z	Deselected	Standby
L	H	H	X	X	High-Z	High-Z	Output Disabled	Active
L	X	X	H	H	High-Z	High-Z	Output Disabled	Active
L	L	H	L	H	Dout	High-Z	Lower Byte Read	Active
L	L	H	H	L	High-Z	Dout	Upper Byte Read	Active
L	L	H	L	L	Dout	Dout	Word Read	Active
L	X	L	L	H	Din	High-Z	Lower Byte Write	Active
L	X	L	H	L	High-Z	Din	Upper Byte Write	Active
L	X	L	L	L	Din	Din	Word Write	Active

Note : X means don't care. (Must be low or high state)

ABSOLUTE MAXIMUM RATINGS¹⁾

Item	Symbol	Ratings	Unit
Voltage on any pin relative to Vss	V _{IN} , V _{OUT}	-0.2 to 3.6	V
Voltage on Vcc supply relative to Vss	V _{CC}	-0.2 to 4.0	V
Power Dissipation	P _D	1.0	W
Storage temperature	T _{STG}	-55 to 150	°C
Operating Temperature	T _A	-40 to 85	°C

1. Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Functional operation should be restricted to recommended operating condition. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

RECOMMENDED DC OPERATING CONDITIONS¹⁾

Item	Symbol	Min	Typ	Max	Unit
Supply voltage	V _{CC}	3.0	3.3	3.6	V
Ground	V _{SS}	0	0	0	V
Input high voltage	V _{IH}	2.2	-	V _{CC} +0.2 ²⁾	V
Input low voltage	V _{IL}	-0.2 ³⁾	-	0.6	V

Note:

1. Commercial products: T_A=0 to 70°C, otherwise specified
Industrial products: T_A=-40 to 85°C, otherwise specified
2. Overshoot: V_{CC}+2.0V in case of pulse width ≤20ns.
3. Undershoot: -2.0V in case of pulse width ≤20ns.
4. Overshoot and undershoot are sampled, not 100% tested.

CAPACITANCE¹⁾ (f=1MHz, T_A=25°C)

Item	Symbol	Test Condition	Min	Max	Unit
Input capacitance	C _{IN}	V _{IN} =0V	-	8	pF
Input/Output capacitance	C _{IO}	V _{IO} =0V	-	10	pF

1. Capacitance is sampled, not 100% tested

DC AND OPERATING CHARACTERISTICS

Item	Symbol	Test Conditions	Min	Typ	Max	Unit
Input leakage current	I _{LI}	V _{IN} =V _{SS} to V _{CC}	-1	-	1	μA
Output leakage current	I _{LO}	$\overline{CS_1}=V_{IH}$, CS ₂ =V _{IL} or $\overline{OE}=V_{IH}$ or $\overline{WE}=V_{IL}$, V _{IO} =V _{SS} to V _{CC}	-1	-	1	μA
Operating power supply current	I _{CC}	I _{IO} =0mA, $\overline{CS_1}=V_{IL}$, CS ₂ =V _{IH} , $\overline{WE}=V_{IH}$, V _{IN} =V _{IH} or V _{IL}	-	-	2	mA
Average operating current	I _{CC1}	Cycle time=1μs, 100%duty, I _{IO} =0mA, $\overline{CS_1} \leq 0.2V$, CS ₂ ≥V _{CC} -0.2V, V _{IN} ≤0.2V or V _{IN} ≥V _{CC} -0.2V	-	-	4	mA
	I _{CC2}	Cycle time=Min, I _{IO} =0mA, 100% duty, $\overline{CS_1}=V_{IL}$, CS ₂ =V _{IH} , V _{IN} =V _{IL} or V _{IH}	-	-	45	mA
Output low voltage	V _{OL}	I _{OL} = 2.1mA			0.4	V
Output high voltage	V _{OH}	I _{OH} = -1.0mA	2.2			V
Standby Current(TTL)	I _{SB}	$\overline{CS_1}=V_{IH}$, CS ₂ =V _{IL} , Other inputs=V _{IH} or V _{IL}	-	-	0.3	mA
Standby Current(CMOS)	I _{SB1}	$\overline{CS_1} \geq V_{CC}-0.2V$, CS ₂ ≥V _{CC} -0.2V($\overline{CS_1}$ controlled) or CS ₂ ≤0.2V(CS ₂ controlled), Other inputs=0~V _{CC}	-	0.5	30 ¹⁾	μA

1. Super low power product=10μA with special handling.

AC OPERATING CONDITIONS

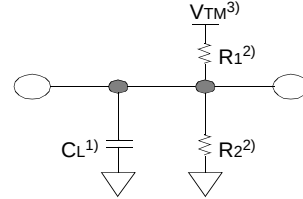
TEST CONDITIONS (Test Load and Input/Output Reference)

Input pulse level: 0.4 to 2.2V

Input rising and falling time: 5ns

Input and output reference voltage: 1.5V

Output load (see right): $C_L = 100\text{pF} + 1\text{TTL}$
 $C_L = 30\text{pF} + 1\text{TTL}$



1. Including scope and jig capacitance

2. $R_1 = 3070\Omega$, $R_2 = 3150\Omega$

3. $V_{TM} = 2.8\text{V}$

AC CHARACTERISTICS ($V_{CC} = 3.0 \sim 3.6\text{V}$, Commercial Products: $T_A = 0$ to 70°C , Industrial products: $T_A = -40$ to 85°C)

Parameter List		Symbol	Speed Bins				Units
			55ns		70ns		
			Min	Max	Min	Max	
Read	Read cycle time	t _{RC}	55	-	70	-	ns
	Address access time	t _{AA}	-	55	-	70	ns
	Chip select to output	t _{CO1} , t _{CO2}	-	55	-	70	ns
	Output enable to valid output	t _{OE}	-	25	-	35	ns
	$\overline{LB}$, $\overline{UB}$ valid to data output	t _{BA}	-	55	-	70	ns
	Chip select to low-Z output	t _{LZ1} , t _{LZ1}	10	-	10	-	ns
	Output enable to low-Z output	t _{OLZ}	5	-	5	-	ns
	$\overline{LB}$, $\overline{UB}$ enable to low-Z output	t _{BLZ}	10	-	10	-	ns
	Output hold from address change	t _{OH}	10	-	10	-	ns
	Chip disable to high-Z output	t _{HZ1} , t _{HZ1}	0	20	0	25	ns
	$\overline{OE}$ disable to high-Z output	t _{OHZ}	0	20	0	25	ns
	$\overline{UB}$, $\overline{LB}$ disable to high-Z output	t _{BHZ}	0	20	0	25	ns
Write	Write cycle time	t _{WC}	55	-	70	-	ns
	Chip select to end of write	t _{CW1} , t _{CW2}	45	-	60	-	ns
	Address set-up time	t _{AS}	0	-	0	-	ns
	Address valid to end of write	t _{AW}	45	-	60	-	ns
	Write pulse width	t _{WP}	40	-	55	-	ns
	Write recovery time	t _{WR}	0	-	0	-	ns
	Write to output high-Z	t _{WHZ}	0	20	0	25	ns
	Data to write time overlap	t _{DW}	25	-	30	-	ns
	Data hold from write time	t _{DH}	0	-	0	-	ns
	End write to output low-Z	t _{OW}	5	-	5	-	ns
	$\overline{LB}$, $\overline{UB}$ valid to end of write	t _{BW}	45	-	60	-	ns

DATA RETENTION CHARACTERISTICS

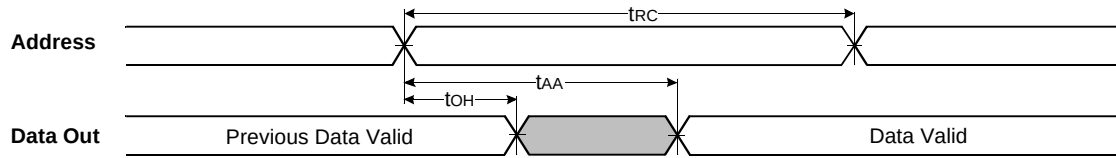
Item	Symbol	Test Condition	Min	Typ	Max	Unit
V_{CC} for data retention	V_{DR}	$\overline{CS}_1 \geq V_{CC} - 0.2\text{V}^{(1)}$	1.5	-	3.6	V
Data retention current	I_{DR}	$V_{CC} = 1.5\text{V}$, $\overline{CS}_1 \geq V_{CC} - 0.2\text{V}^{(1)}$	-	0.5	6 ⁽²⁾	μA
Data retention set-up time	t_{SDR}	See data retention waveform	0	-	-	ms
Recovery time	t_{RDR}		t_{RC}	-	-	

1. $\overline{CS}_1 \geq V_{CC} - 0.2\text{V}$, $\overline{CS}_2 \geq V_{CC} - 0.2\text{V}$ ($\overline{CS}_1$ controlled) or $\overline{CS}_2 \geq V_{CC} - 0.2\text{V}$ ($\overline{CS}_2$ controlled).

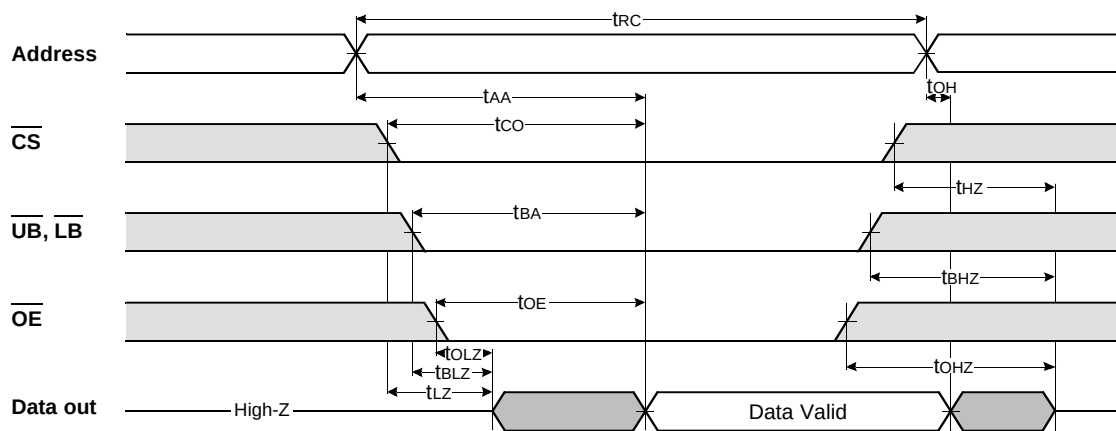
2. Super low power product = $4\mu\text{A}$ with special handling.

TIMMING DIAGRAMS

TIMING WAVEFORM OF READ CYCLE(1) (Address Controlled, $\overline{CS}=\overline{OE}=V_{IL}$, $\overline{WE}=V_{IH}$, $\overline{UB}$ or/and $\overline{LB}=V_{IL}$)



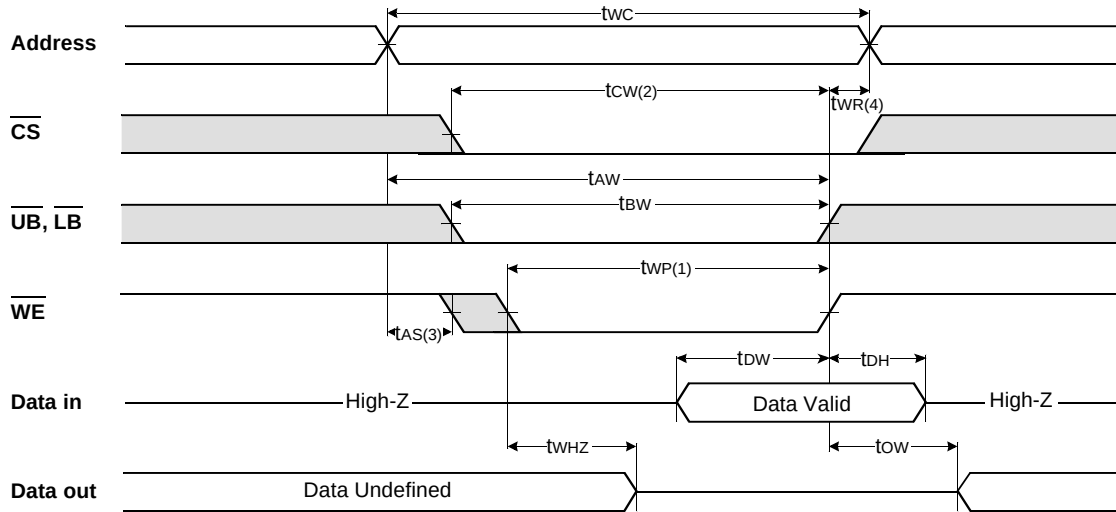
TIMING WAVEFORM OF READ CYCLE(2) ($\overline{WE}=V_{IH}$)



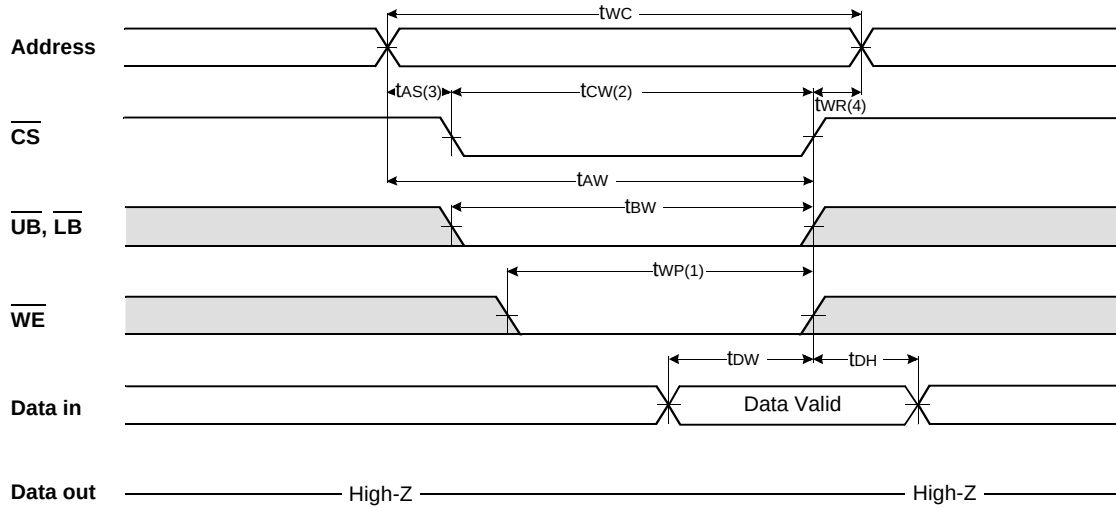
NOTES (READ CYCLE)

1. t_{HZ} and t_{OHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referenced to output voltage levels.
2. At any given temperature and voltage condition, $t_{HZ}(\text{Max.})$ is less than $t_{LZ}(\text{Min.})$ both for a given device and from device to device interconnection.

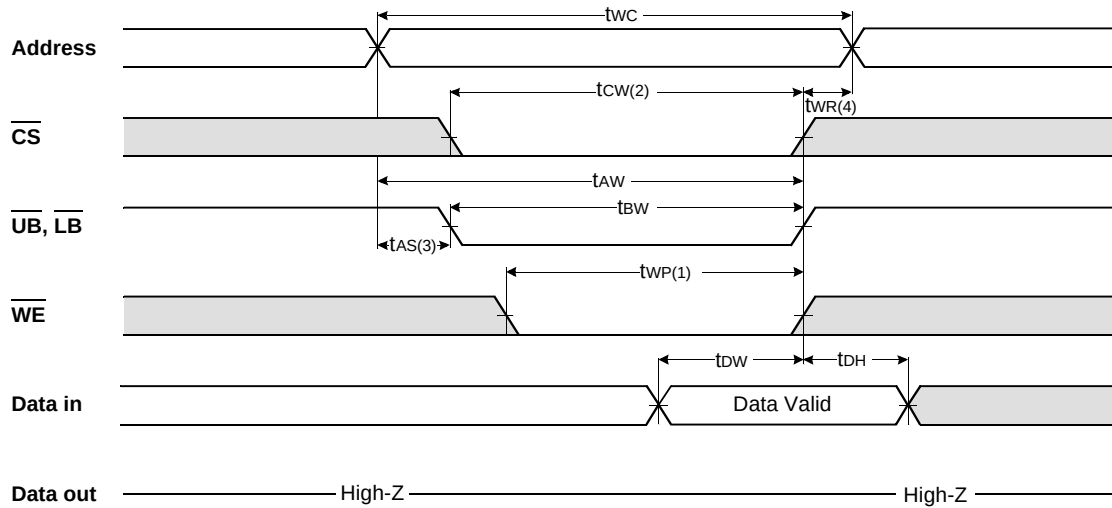
TIMING WAVEFORM OF WRITE CYCLE(1) ($\overline{\text{WE}}$ Controlled)



TIMING WAVEFORM OF WRITE CYCLE(2) ($\overline{\text{CS}}$ Controlled)



TIMING WAVEFORM OF WRITE CYCLE(3) ($\overline{UB}$, $\overline{LB}$ Controlled)

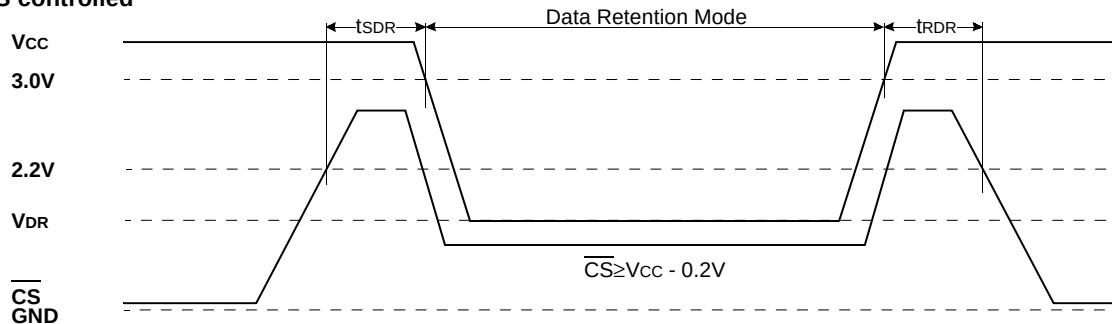


NOTES (WRITE CYCLE)

1. A write occurs during the overlap(t_{WP}) of low $\overline{CS}$ and low $\overline{WE}$. A write begins when $\overline{CS}$ goes low and $\overline{WE}$ goes low with asserting $\overline{UB}$ or $\overline{LB}$ for single byte operation or simultaneously asserting $\overline{UB}$ and $\overline{LB}$ for double byte operation. A write ends at the earliest transition when $\overline{CS}$ goes high and $\overline{WE}$ goes high. The t_{WP} is measured from the beginning of write to the end of write.
2. t_{CW} is measured from the $\overline{CS}$ going low to end of write.
3. t_{AS} is measured from the address valid to the beginning of write.
4. t_{WR} is measured from the end of write to the address change. t_{WR} applied in case a write ends as $\overline{CS}$ or $\overline{WE}$ going high.

DATA RETENTION WAVE FORM

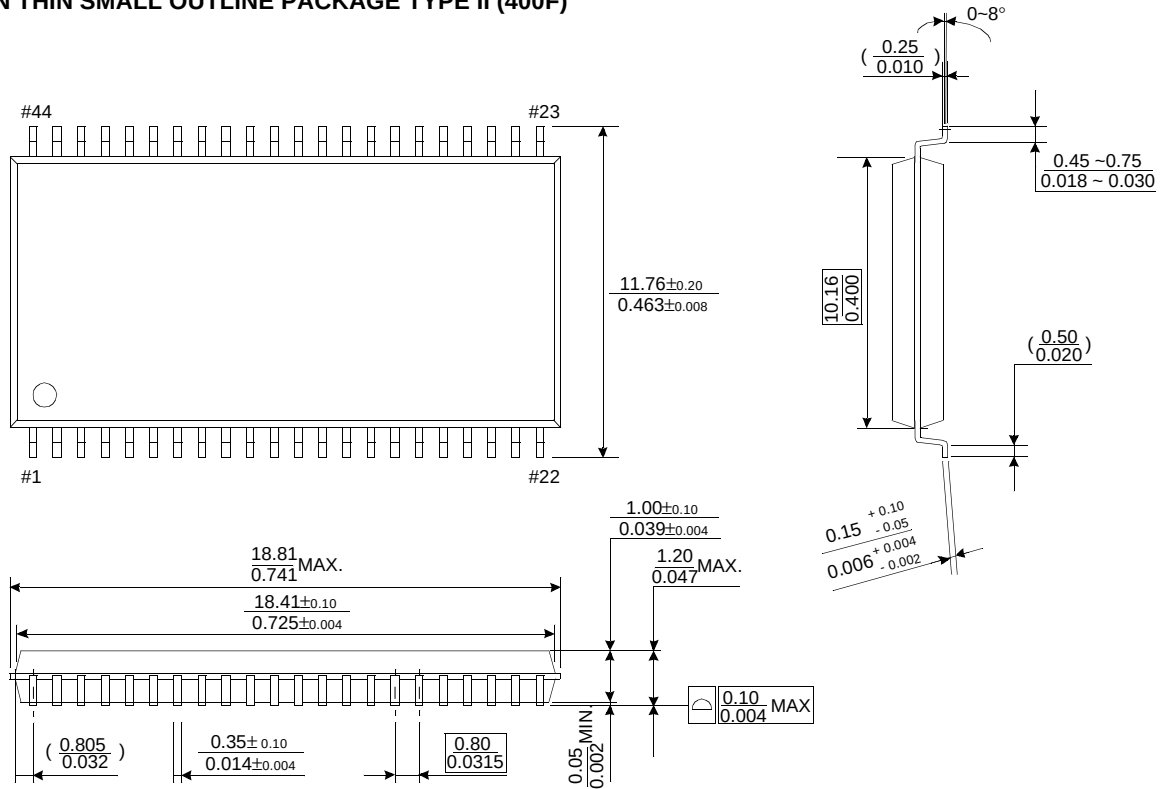
$\overline{CS}$ controlled



PACKAGE DIMENSION

Unit: millimeters

44 PIN THIN SMALL OUTLINE PACKAGE TYPE II (400F)



44 PIN THIN SMALL OUTLINE PACKAGE TYPE II (400R)

